TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

# 2SK3566

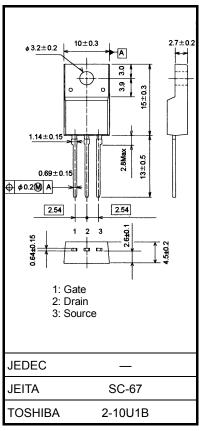
### **Switching Regulator Applications**

Unit: mm

- Low drain-source ON resistance: RDS (ON) =  $5.6 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 2.0 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 720 \, V)$
- Enhancement-mode:  $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	900	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	900	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	2.5		
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	7.5	Α	
Drain power dissipati	on (Tc = 25°C)	PD	40	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	216	mJ	
Avalanche current		I <sub>AR</sub>	2.5	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	4	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

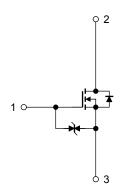


Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.125	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W



- Note 1: Please use devices on conditions that the channel temperature is below 150°C.
- Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$ , L = 63.4 mH,  $I_{AR} = 2.5 \text{ A}$ ,  $R_G = 25 \Omega$
- Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

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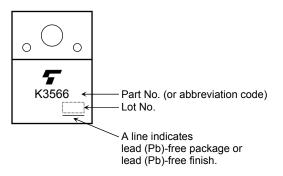
# **Electrical Characteristics (Ta = 25°C)**

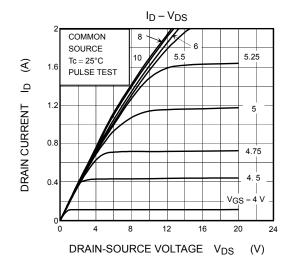
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{GS} = 0 \ V$	±30	_	_	V
Drain cut-off curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V	_	_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	900	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.5 A	_	5.6	6.4	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 1.5 A	1.0	2.0	_	S
Input capacitance	9	C <sub>iss</sub>		_	470	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	10	_	pF
Output capacitance		C <sub>oss</sub>		_	50	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{DD} \simeq 200 \text{ V}$ $V_{DD} \simeq 200 \text{ V}$	_	20	_	
	Turn-on time	t <sub>on</sub>		_	60	_	
	Fall time	t <sub>f</sub>		_	30	_	ns .
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, $t_W = 10 \mu s$	_	100	_	
Total gate charge		Qg		_	12	_	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$	_	7	_	nC
Gate-drain charge		Q <sub>gd</sub>		_	5		

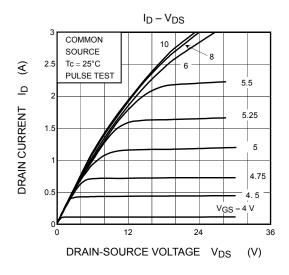
# Source-Drain Ratings and Characteristics (Ta = 25°C)

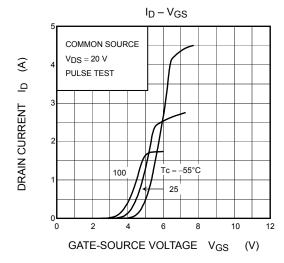
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	2.5	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	7.5	Α
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 2.5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 2.5 \text{ A}, V_{GS} = 0 \text{ V},$	_	720	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/μs		3.6	_	μС

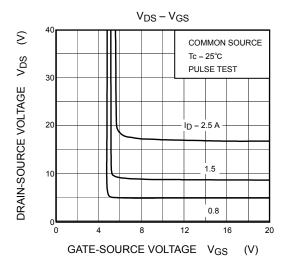
# Marking

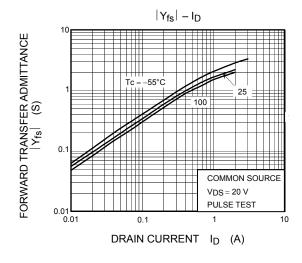


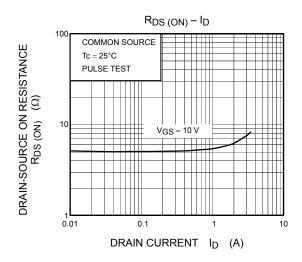




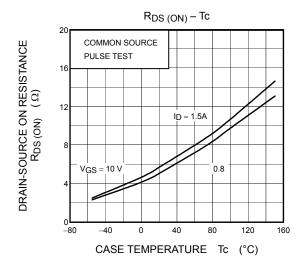


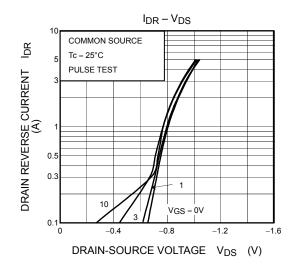


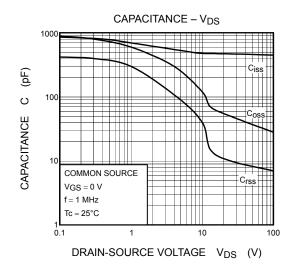


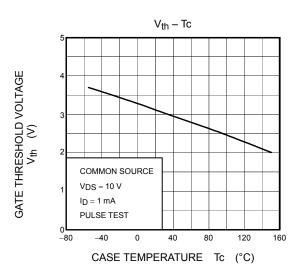


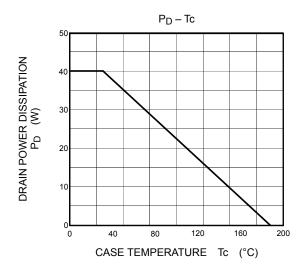
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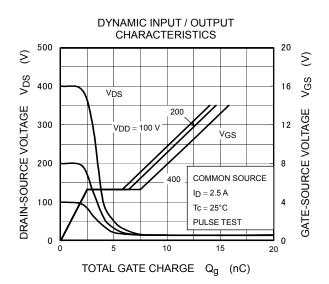


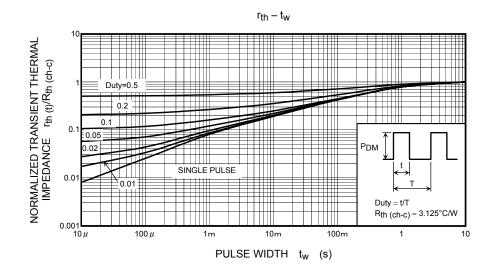


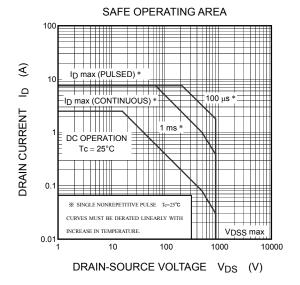


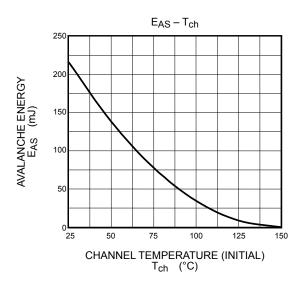


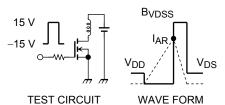












$$R_G = 25 \Omega$$

$$V_{DD} = 90 \text{ V, L} = 43.4 \text{mH}$$

$$E_{AS} = \frac{1}{2} \cdot \text{L} \cdot \text{I}^2 \cdot \left(\frac{\text{BVDSS}}{\text{BVDSS} - \text{VDD}}\right)$$

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